



STM8501

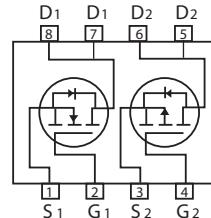
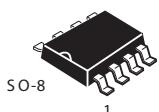
SamHop Microelectronics Corp.

Jan.10 2006

Dual Enhancement Mode Field Effect Transistor (N and P Channel)

PRODUCT SUMMARY (N-Channel)		
V _{DSS}	I _D	R _{D(S)ON} (mΩ) Max
55V	5A	50 @ V _{GS} = 10V
		70 @ V _{GS} = 4.5V

PRODUCT SUMMARY (P-Channel)		
V _{DSS}	I _D	R _{D(S)ON} (mΩ) Max
-55V	- 3.5A	80 @ V _{GS} = -10V
		100 @ V _{GS} = -4.5V



ABSOLUTE MAXIMUM RATINGS (T_A=25°C unless otherwise noted)

Parameter	Symbol	N-Channel	P-Channel	Unit	
Drain-Source Voltage Rating	V _{spike} ^d	60	-60	V	
Drain-Source Voltage	V _{DS}	55	-55	V	
Gate-Source Voltage	V _{GS}	±20	±20	V	
Drain Current-Continuous ^a @ T _a	25°C	I _D	5	-3.5	A
	70°C		4.2	-2.8	A
-Pulsed ^b	I _{DM}		22	-18	A
Drain-Source Diode Forward Current ^a	I _S		1.7	-1.7	A
Maximum Power Dissipation ^a	T _a =25°C	P _D	2		W
	T _a =70°C		1.44		
Operating Junction and Storage Temperature Range	T _J , T _{STG}	-55 to 150		°C	

THERMAL CHARACTERISTICS

Thermal Resistance, Junction-to-Ambient ^a	R _{θJA}	62.5	°C/W
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N-Channel ELECTRICAL CHARACTERISTICS (TA = 25 °C unless otherwise noted)

Parameter	Symbol	Condition	Min	Typ ^c	Max	Unit
OFF CHARACTERISTICS						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} = 0V, I _D = 250µA	55			V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 44V, V _{GS} = 0V		1		µA
Gate-Body Leakage	I _{GSS}	V _{GS} = ±20V, V _{DS} = 0V		±100		nA
ON CHARACTERISTICS ^b						
Gate Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250µA	1.0	1.7	3.0	V
Drain-Source On-State Resistance	R _{DSON}	V _{GS} = 10V, I _D = 4.5A		34	50	m ohm
		V _{GS} = 4.5V, I _D = 4A		45	70	m ohm
On-State Drain Current	I _{D(ON)}	V _{DS} = 5V, V _{GS} = 10V	15			A
Forward Transconductance	g _F	V _{DS} = 5V, I _D = 4.5A		15		S
DYNAMIC CHARACTERISTICS ^c						
Input Capacitance	C _{ISS}	V _{DS} = 25V, V _{GS} = 0V f = 1.0MHz		930		pF
Output Capacitance	C _{OSS}			85		pF
Reverse Transfer Capacitance	C _{RSS}			50		pF
Gate resistance	R _G	V _{GS} = 0V, V _{DS} = 0V, f = 1.0MHz		3.9		ohm
SWITCHING CHARACTERISTICS ^c						
Turn-On Delay Time	t _{D(ON)}	V _{DD} = 30V I _D = 1 A V _{GS} = 10V R _{GEN} = 6 ohm		17		ns
Rise Time	t _r			14		ns
Turn-Off Delay Time	t _{D(OFF)}			29		ns
Fall Time	t _f			5		ns
Total Gate Charge	Q _G	V _{DS} = 30V, I _D = 4.5A, V _{GS} = 10V		20		nC
		V _{DS} = 30V, I _D = 4.5A, V _{GS} = -4.5V		9.5		nC
Gate-Source Charge	Q _{GS}	V _{DS} = 30V, I _D = 4.5 A V _{GS} = 10V		2.9		nC
Gate-Drain Charge	Q _{GD}			4.5		nC

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P-Channel ELECTRICAL CHARACTERISTICS (TA = 25 °C unless otherwise noted)

Parameter	Symbol	Condition	Min	Typ ^c	Max	Unit
OFF CHARACTERISTICS						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} = 0V, I _D = -250μA	-55			V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = -44V, V _{GS} = 0V		-1		μA
Gate-Body Leakage	I _{GSS}	V _{GS} = ±20V, V _{DS} = 0V		±100		nA
ON CHARACTERISTICS ^b						
Gate Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = -250μA	-1.0	-1.7	-3.0	V
Drain-Source On-State Resistance	R _{DSON}	V _{GS} = -10V, I _D = -3A		60	80	m ohm
		V _{GS} = -4.5V, I _D = -2A		80	100	m ohm
On-State Drain Current	I _{D(ON)}	V _{DS} = -5V, V _{GS} = -10V	10			A
Forward Transconductance	g _F	V _{DS} = -5V, I _D = -3A		8.5		S
DYNAMIC CHARACTERISTICS ^c						
Input Capacitance	C _{ISS}	V _{DS} = -30V, V _{GS} = 0V f = 1.0MHz		900		pF
Output Capacitance	C _{OSS}			85		pF
Reverse Transfer Capacitance	C _{RSS}			58		pF
Gate resistance	R _G	V _{GS} = 0V, V _{DS} = 0V, f = 1.0MHz		4.2		ohm
SWITCHING CHARACTERISTICS ^c						
Turn-On Delay Time	t _{D(ON)}	V _{DD} = -30V R _L = 30 ohm V _{GS} = -10V R _{GEN} = 6 ohm		13		ns
Rise Time	t _r			16		ns
Turn-Off Delay Time	t _{D(OFF)}			84		ns
Fall Time	t _f			24		ns
Total Gate Charge	Q _G	V _{DS} = -30V, I _D = -3A, V _{GS} = -10V		18.5		nC
		V _{DS} = -30V, I _D = -3A, V _{GS} = -4.5V		9.1		nC
Gate-Source Charge	Q _{GS}	V _{DS} = -30V, I _D = -3 A V _{GS} = -10V		1.8		nC
Gate-Drain Charge	Q _{GD}			4.5		nC

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ELECTRICAL CHARACTERISTICS ($T_A=25^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Condition	Min	Typ ^c	Max	Unit
DRAIN-SOURCE DIODE CHARACTERISTICS ^b						
Diode Forward Voltage	V_{SD}	$V_{GS} = 0\text{V}, I_S = 1.7\text{A}$ $V_{GS} = 0\text{V}, I_S = -1.7\text{A}$	N-Ch		0.8 -0.78	1.2 -1.2
		P-Ch				V

Notes

- a. Surface Mounted on FR4 Board, $t \leq 1\text{sec}$.
- b. Pulse Test: Pulse Width $\leq 300\ \mu\text{s}$, Duty Cycle $\leq 2\%$.
- c. Guaranteed by design, not subject to production testing.
- d. Guaranteed when external $R_g=6\ \Omega$ and $t_f < t_{f\ max}$.

N-Channel

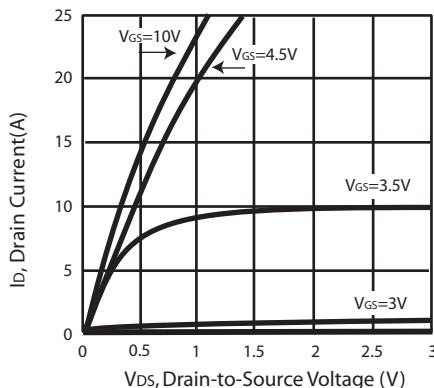


Figure 1. Output Characteristics

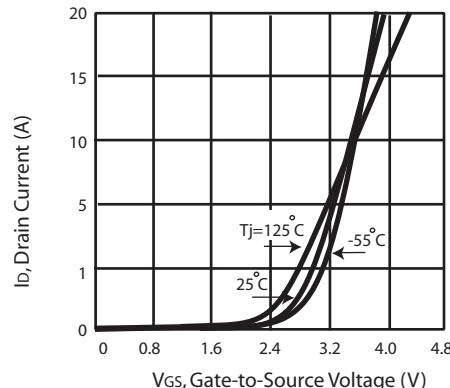


Figure 2. Transfer Characteristics

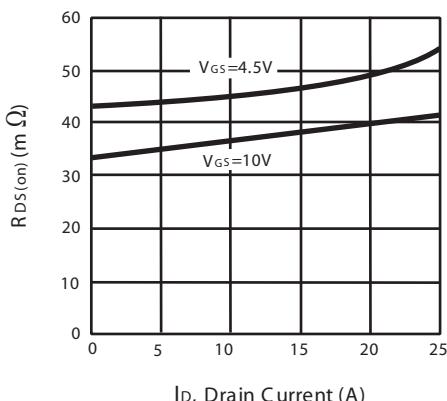


Figure 3. On-Resistance vs. Drain Current and Gate Voltage

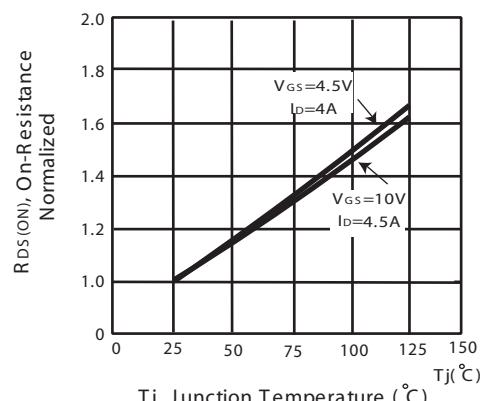


Figure 4. On-Resistance Variation with Drain Current and Temperature

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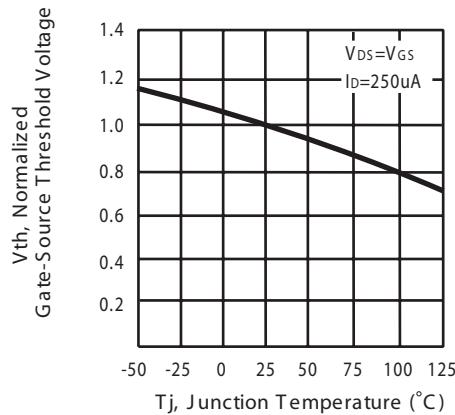


Figure 5. Gate Threshold Variation with Temperature

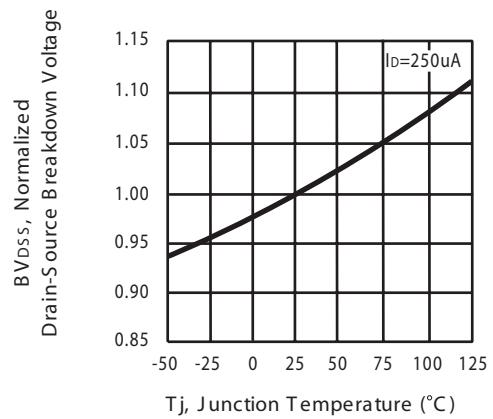


Figure 6. Breakdown Voltage Variation with Temperature

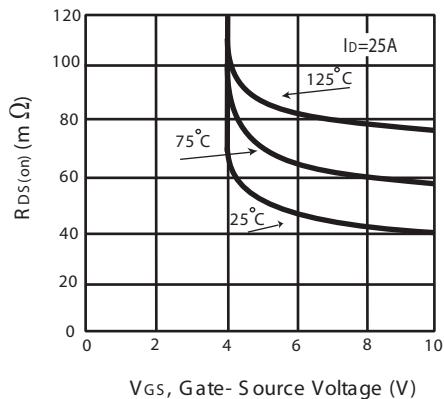


Figure 7. On-Resistance vs. Gate-Source Voltage

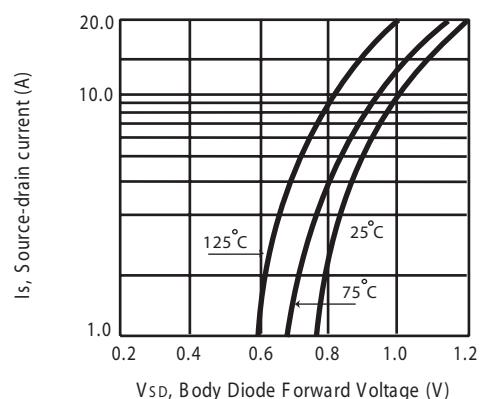


Figure 8. Body Diode Forward Voltage Variation with Source Current

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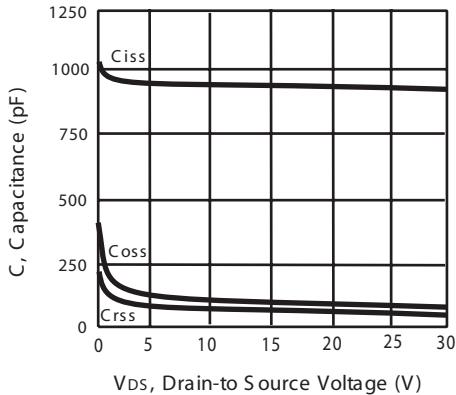


Figure 9. Capacitance

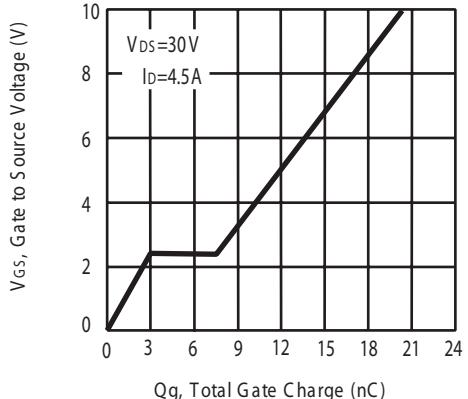


Figure 10. Gate Charge

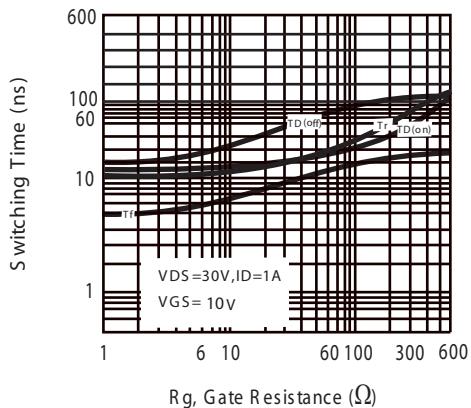


Figure 11. switching characteristics

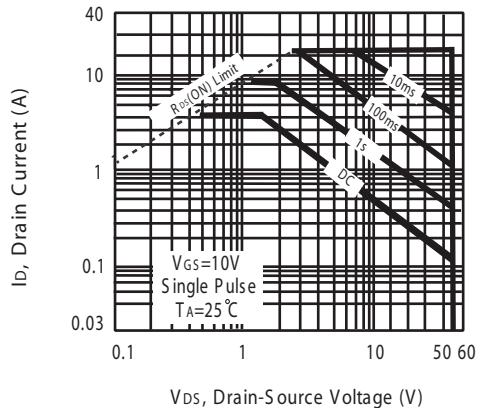


Figure 12. Maximum Safe Operating Area

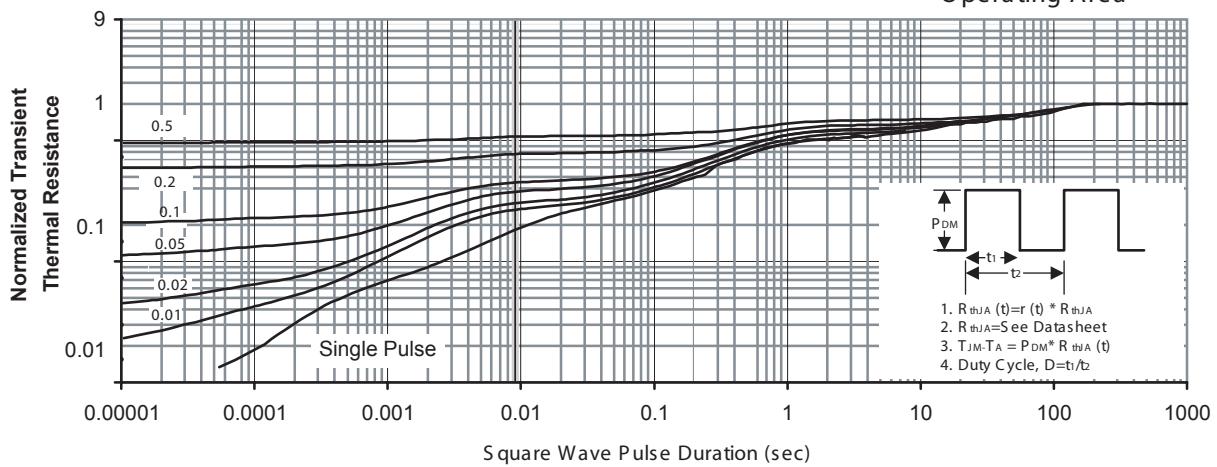


Figure 13. Normalized Thermal Transient Impedance Curve

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P-Channel

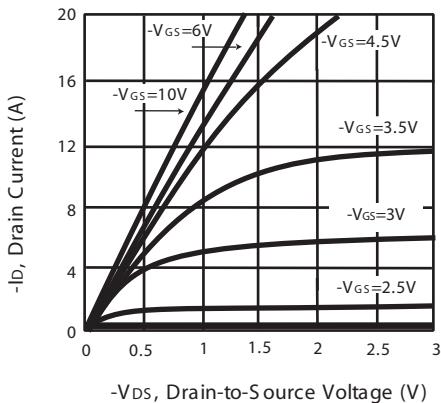


Figure 1. Output Characteristics

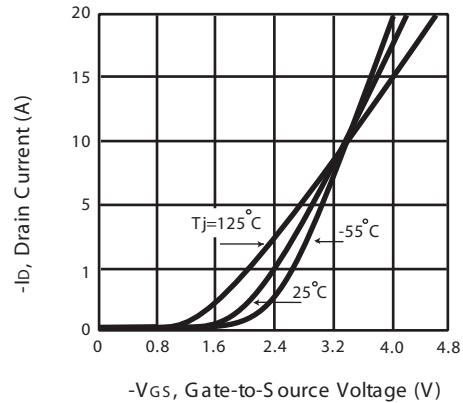


Figure 2. Transfer Characteristics

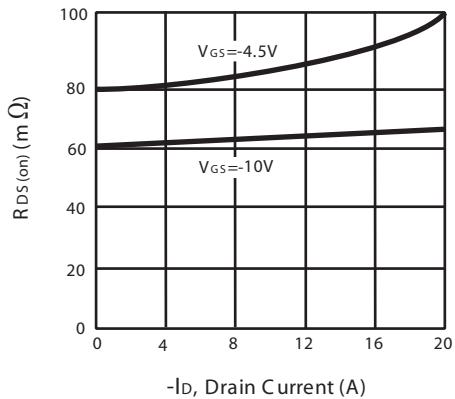


Figure 3. On-Resistance vs. Drain Current and Gate Voltage

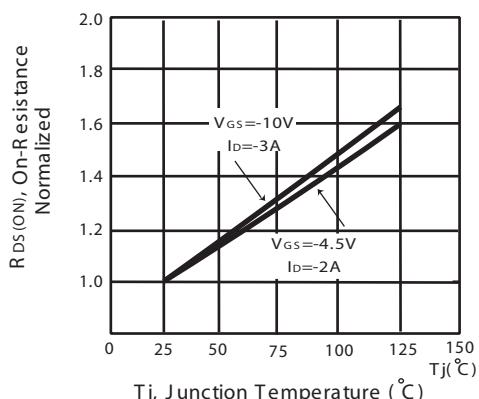


Figure 4. On-Resistance Variation with Drain Current and Temperature

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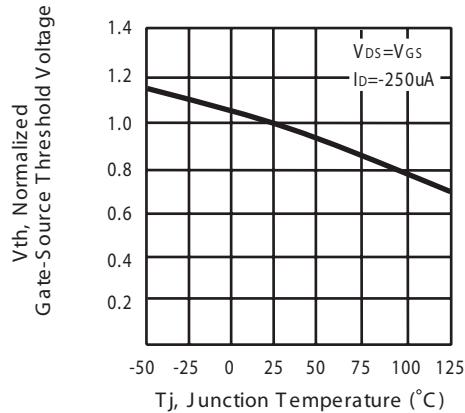


Figure 5. Gate Threshold Variation with Temperature

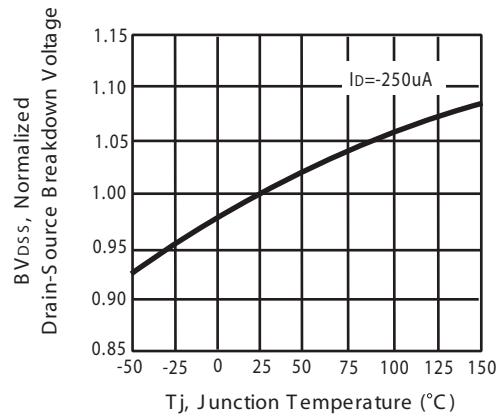


Figure 6. Breakdown Voltage Variation with Temperature

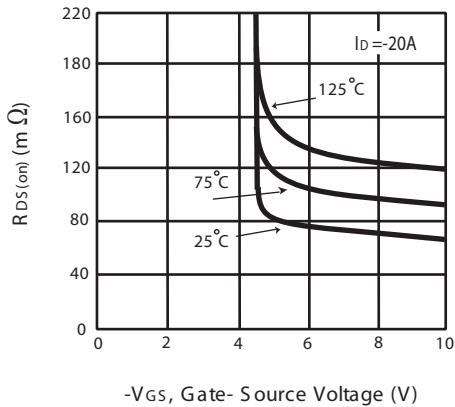


Figure 7. On-Resistance vs. Gate-Source Voltage

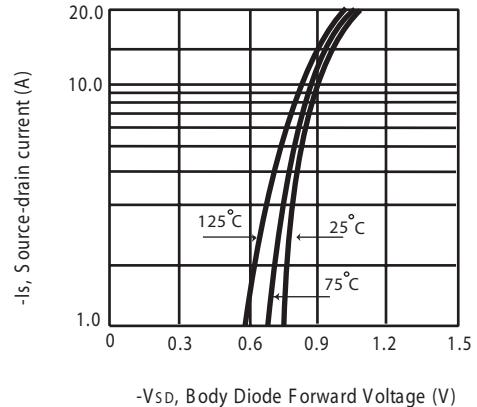


Figure 8. Body Diode Forward Voltage Variation with Source Current

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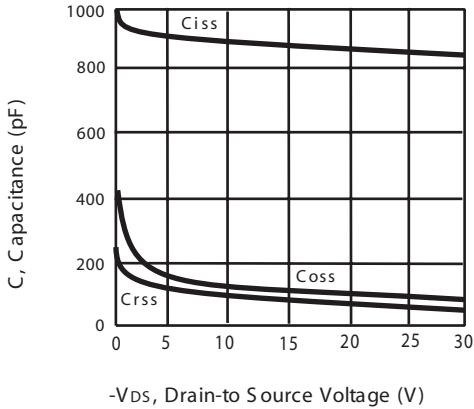


Figure 9. Capacitance

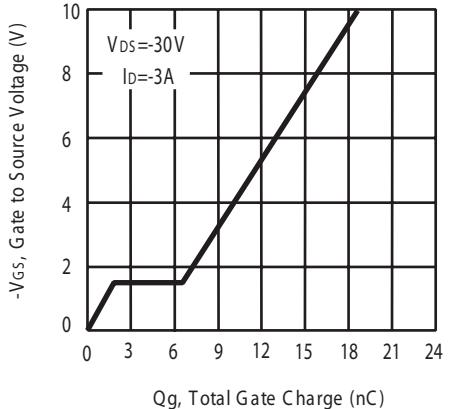


Figure 10. Gate Charge

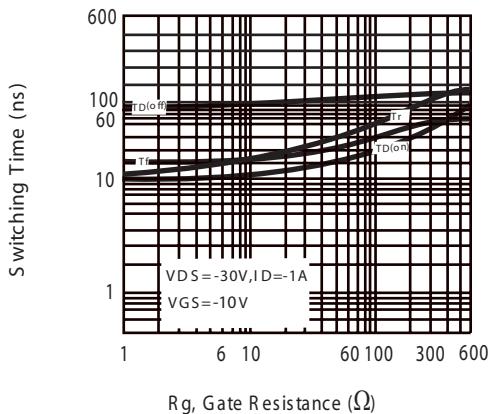


Figure 11. switching characteristics

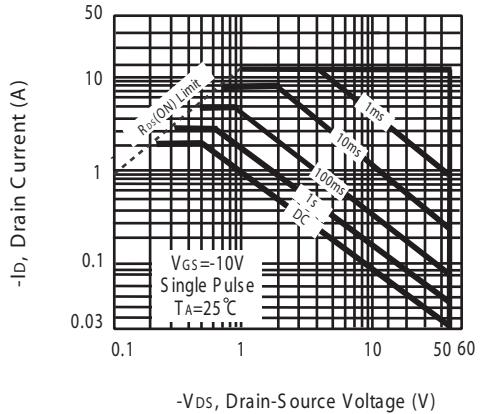


Figure 12. Maximum Safe Operating Area

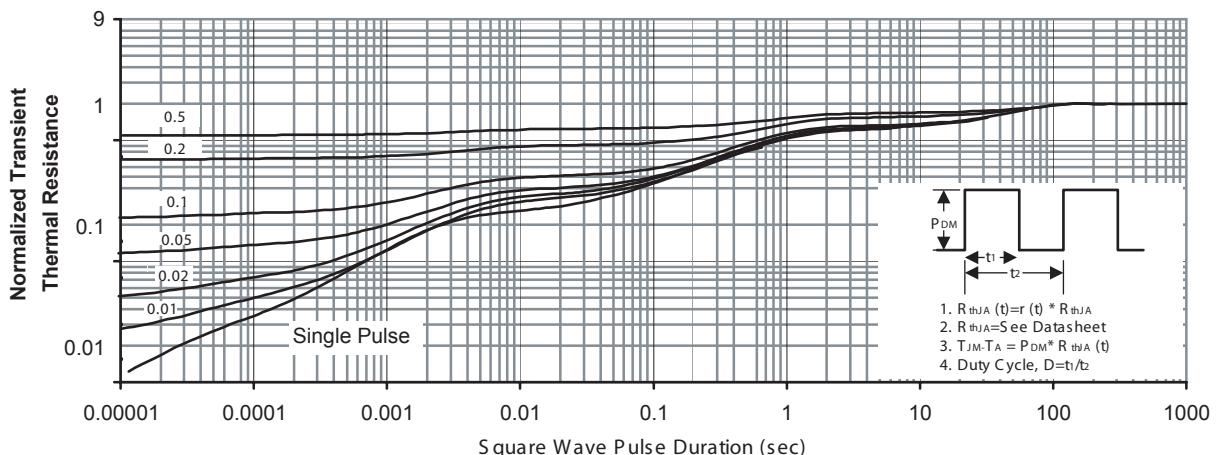
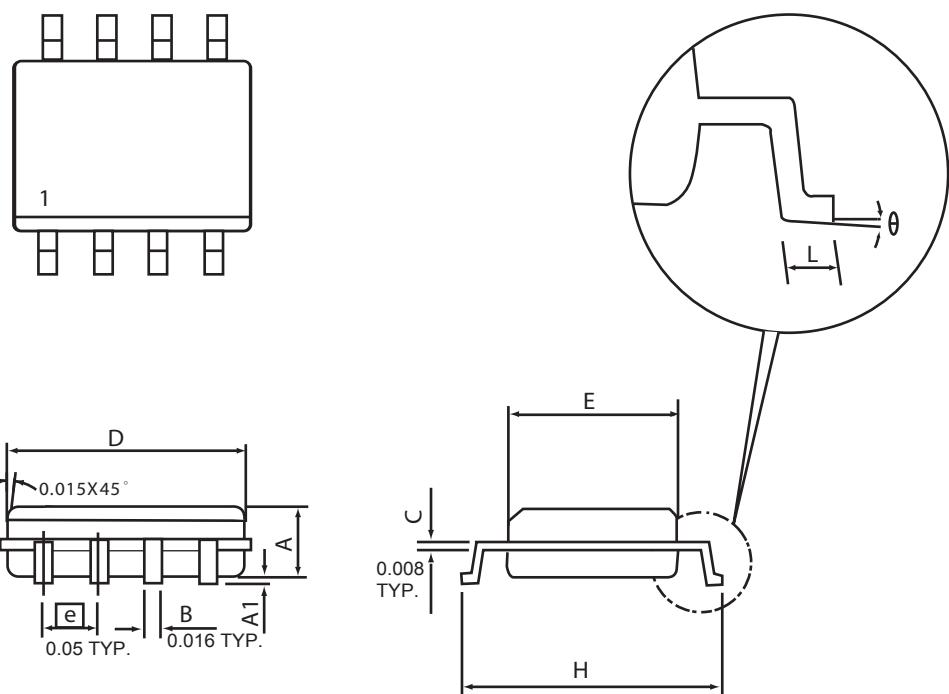


Figure 13. Normalized Thermal Transient Impedance Curve

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PACKAGE OUTLINE DIMENSIONS

SO-8

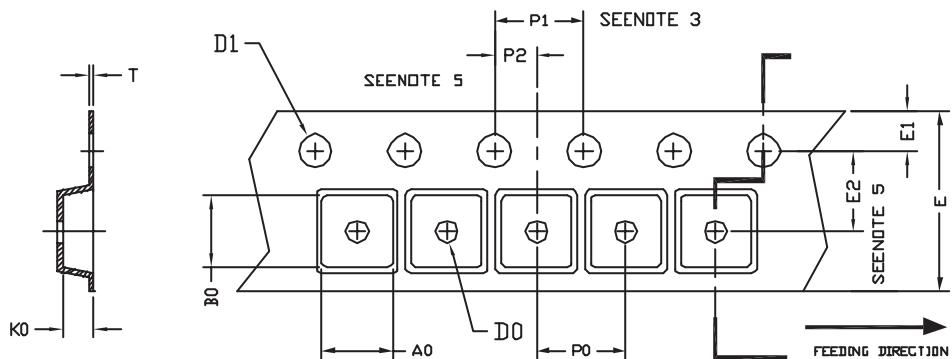


SYMBOLS	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	1.35	1.75	0.053	0.069
A1	0.10	0.25	0.004	0.010
D	4.80	4.98	0.189	0.196
E	3.81	3.99	0.150	0.157
H	5.79	6.20	0.228	0.244
L	0.41	1.27	0.016	0.050
θ	0°	8°	0°	8°

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SO-8 Tape and Reel Data

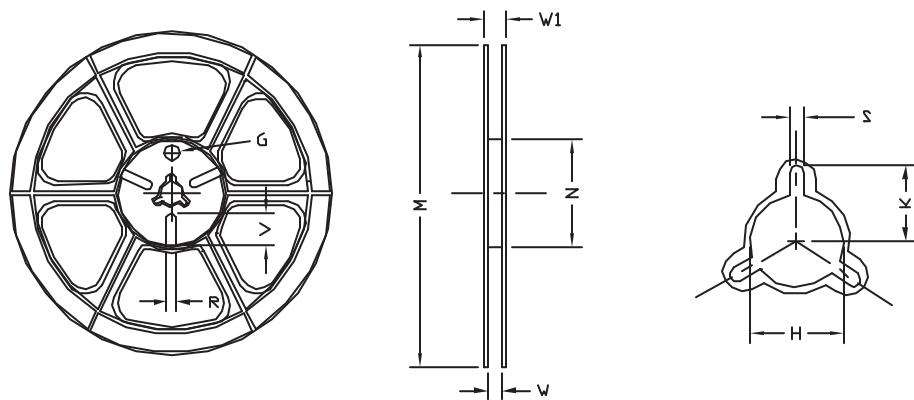
SO-8 Carrier Tape



unit:mm

PACKAGE	A0	B0	K0	D0	D1	E	E1	E2	P0	P1	P2	T
SOP 8N 150mil	6.40	5.20	2.10	$\phi 1.5$ (MIN)	$\phi 1.5$ $+ 0.1$ $- 0.0$	12.0 ± 0.3	1.75	5.5 ± 0.05	8.0	4.0	2.0 ± 0.05	0.3 ± 0.05

SO-8 Reel



UNIT:mm

TAPE SIZE	REEL SIZE	M	N	W	W1	H	K	S	G	R	V
12 mm	$\phi 330$	330 ± 1	62 ± 1.5	12.4 $+ 0.2$	16.8 $- 0.4$	$\phi 12.75$ $+ 0.15$	---	2.0 ± 0.15	---	---	---